MOSFET - Power, N-Channel, SO-8 30 V, 12.5 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Converters
- Points of Loads
- Power Load Switch
- Motor Controls

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage	V_{DSS}	30	V		
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain	Steady	T _A = 25°C	I _D	10.3	Α
Current R _{θJA} (Note 1)	State	T _A = 70°C		8.3	
Power Dissipation $R_{\theta JA}$ (Note 1)	Steady State	T _A = 25°C	P _D	1.35	W
Continuous Drain	Steady	T _A = 25°C	I _D	8.0	Α
Current R _{θJA} (Note 2)	State	T _A = 70°C		6.4	
Power Dissipation $R_{\theta JA}$ (Note 2)	T _A = 25°C		P _D	0.8	W
Continuous Drain	Steady T _A = 25°C		I _D	12.5	Α
Current $R_{\theta JA}$, $t \le 10 s$ (Note 1)	State	T _A = 70°C		10	
Power Dissipation $R_{\theta JA}$, $t \le 10 \text{ s(Note 1)}$	Steady State			2.0	W
Pulsed Drain Current	$T_A = 25^{\circ}$	C, t _p = 10 μs	I _{DM}	100	Α
Operating Junction and S	T _J , T _{stg}	–55 to 150	ç		
Source Current (Body Did	IS	2.0	Α		
Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{DD} = 30 \text{ V}, \text{V}_{L} = 11 \text{ A}_{pk}, L = 1.0 \text{ mH}, F$	E _{AS}	60.5	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	92.7	°C/W
Junction-to-Ambient - t ≤ 10 s (Note 1)	$R_{\theta JA}$	61.7	
Junction-to-Foot (Drain)	$R_{\theta JF}$	23.5	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	155.6	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

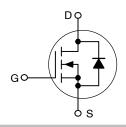


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	8.4 mΩ @ 10 V	12.5 A
	11 mΩ @ 4.5 V	12.5 A

N-Channel



PIN 1 Source SO-8 Source

CASE 751

STYLE 12

MARKING DIAGRAM/ PIN ASSIGNMENT

Source Drain
Source Drain
Source Drain
Source Drain
Top View

4939N = Device Code A = Assembly Location Y = Year

WW = Work Week
■ Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4939NR2G	SO-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

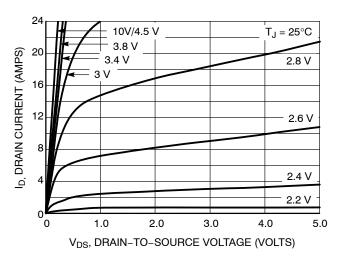
1. 2.	Surfacemounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces). Surfacemounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 2	50 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				13.8		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}		T _J = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$	T _J = 125°C			10	1
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.0		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	7.5 A		7.0	8.4	mΩ
		V _{GS} = 4.5 V, I _D =	6.5 A		9.0	11	1
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	7.5 A		23.8		S
CHARGES, CAPACITANCES AND G	ATE RESISTAN	ICE					
Input Capacitance	C _{iss}				2000		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz	, V _{DS} = 25 V		620		1
Reverse Transfer Capacitance	C _{rss}				16		1
Total Gate Charge	Q _{G(TOT)}				12.4		nC
Threshold Gate Charge	Q _{G(TH)}				3.3		
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15^{\circ}$	V, I _D = 7.5 A		5.3		
Gate-to-Drain Charge	Q_{GD}		ŀ		1.85		1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V	V, I _D = 7.5 A		25		nC
SWITCHING CHARACTERISTICS (N	ote 4)						
Turn-On Delay Time	t _{d(on)}				10.6		ns
Rise Time	t _r	VGS = 10 V. VDS =	= 15 V.		3.1		1
Turn-Off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, V_{DS} = 1.0 \text{ A}, R_{G} = 1.0 \text{ A}$	6.0 Ω [′]		36.7		1
Fall Time	t _f		ŀ		21.5		1
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	V _{SD}	., .,,	T _J = 25°C		0.73	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 2.0 \text{ A}$	T _J = 125°C		0.57		1
Reverse Recovery Time	t _{RR}				36.3		ns
Charge Time	ta	V_{GS} = 0 V, d_{IS}/d_t = 100 A/ μ s, I_S = 2.0 A			17.8		1
Discharge Time	t _b				18.5		1
Reverse Recovery Charge	Q _{RR}				32		nC
PACKAGE PARASITIC VALUES			•				
Source Inductance	L _S				0.66		nH
Drain Inductance	L _D	T _A = 25°C			0.2		1
Gate Inductance	L _G				1.5		1
Gate Resistance	R_{G}				0.4	1.0	Ω

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

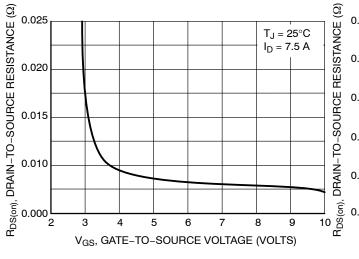
TYPICAL PERFORMANCE CURVES



 $V_{DS} \geq 10 \; V$ 40 _{ID.} DRAIN CURRENT (AMPS) 35 30 25 20 15 $T_{\rm J} = 125^{\circ}{\rm C}$ 10 5 $T_{.1} = 25^{\circ}$ -55°C 0 0 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



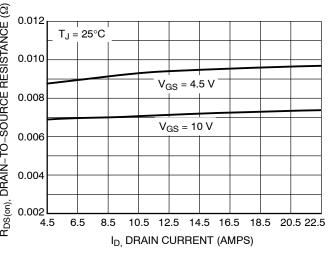
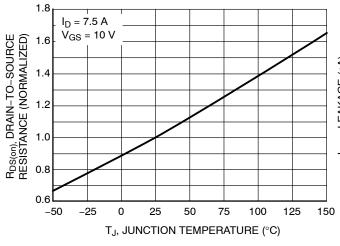


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



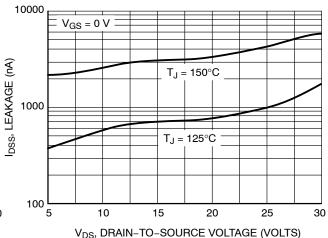


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

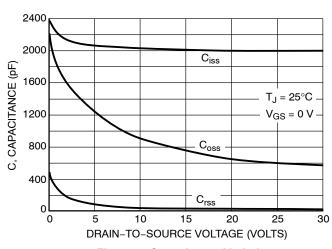


Figure 7. Capacitance Variation

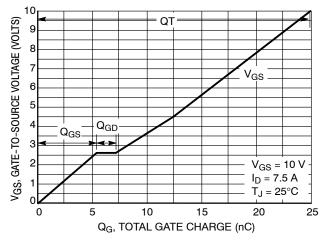


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

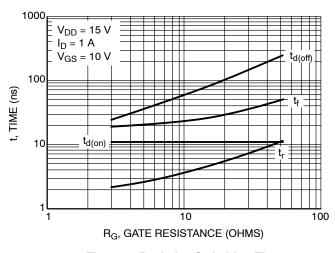


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

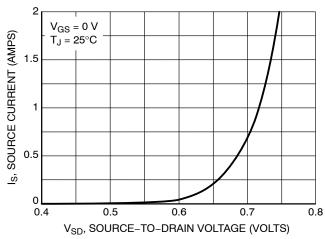


Figure 10. Diode Forward Voltage vs. Current

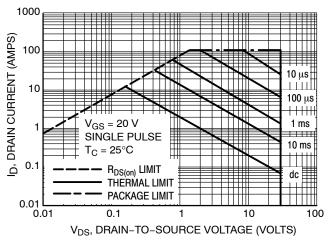


Figure 11. Maximum Rated Forward Biased Safe Operating Area

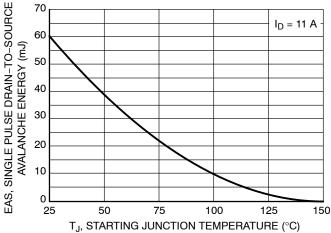
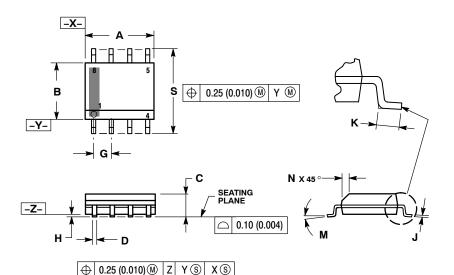


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature



SOIC-8 NB CASE 751-07 **ISSUE AK**

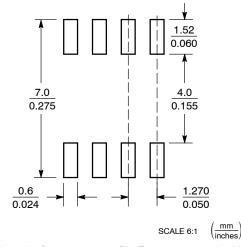
DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80 4.00		0.150	0.157	
C	1.35	1.75	0.053	0.069	
D	0.33 0.51		0.013	0.020	
G	1.27	1.27 BSC		0 BSC	
Н	0.10	0.10 0.25		0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
M	0 ° 8 °		0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location = Wafer Lot

= Year = Work Week = Pb-Free Package XXXXXX AYWW AYWW Ŧ \mathbb{H} Discrete **Discrete** (Pb-Free)

XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

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DATE 16 FEB 2011

			27112 101 22 2
STYLE 1: PIN 1. EMITTER 2. COLLECTOR 3. COLLECTOR 4. EMITTER 5. EMITTER 6. BASE 7. BASE 8. EMITTER	STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 5. BASE, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1	
STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. DRAIN 5. GATE 6. GATE 7. SOURCE 8. SOURCE	STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE	STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd	STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1
STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 3. COLLECTOR, DIE #2 4. EMITTER, COMMON 5. EMITTER, COMMON 6. BASE, DIE #2 7. BASE, DIE #1 8. EMITTER, COMMON	STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. BIAS 2 7. INPUT 8. GROUND STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE	STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 13: PIN 1. N.C. 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN	STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	8. DHAIN 1 STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
6. VEE 7. GND 8. ACC STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3. CATHODE 3 4. CATHODE 4 5. CATHODE 5 6. COMMON ANODE 7. COMMON ANODE 8. CATHODE 6	STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	a COLLECTOR/ANODE
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 29: PIN 1. BASE, DIE #1 2. EMITTER, #1 3. BASE, #2 4. EMITTER, #2 5. COLLECTOR, #2 6. COLLECTOR, #2 7. COLLECTOR, #1 8. COLLECTOR, #1	STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		

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